## Notice of References Cited

Ī	Application/Control No.	Applicant(s)/Pater	nt Under
	10/572,907	Reexamination NAKAZAWA, NAG	OFUMI
	Examiner	Art Unit	
	Timothy J. Henn	2622	Page 1 of 1

## U.S. PATENT DOCUMENTS

_					
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0135672	09-2002	Sezan et al.	348/36
*	В	US-6,834,128	12-2004	Altunbasak et al.	382/284
*	С	US-6,307,550	10-2001	Chen et al.	345/418
*	D	US-2005/0008254	01-2005	Ouchi et al.	382/284
*	Е	US-2005/0104902	05-2005	Zhang et al.	345/629
*	F	US-6,392,658	05-2002	Oura, Koutatsu	345/629
*	G	US-7,424,218	09-2008	Baudisch et al.	396/322
*	Н	US-6,941,029	09-2005	Hatori, Kenji	382/284
	1	US-			
	J	US-			
	к	US-			
	٦	US-			
	м	US-			

	FOREIGN PATENT DOCUMENTS					
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## NON DATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U			
	v			
	w			
	x			

"A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.